

Search Notes

Application No.

09/912,398

Examiner

Mary C Hogan

Applicant(s)

INANAMI ET AL.

Art Unit

2123

SEARCHED

Class	Subclass	Date	Examiner
703	2,20	12/16/2004	MCH
700	105-107	12/16/2004	MCH
700	19,182	12/16/2004	MCH
716	21	12/16/2004	MCH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Name Search: EAST, IEEE	12/15/2004	MCH
IEEE: charged particle beam, character projection, semiconductor <and> manufacture <and> order <and> design <and> cost <and>	12/16/2004	MCH
ACM: character projection,manufacture, mask customer design	12/16/2004	MCH
IEEE: semiconductor <and> design <and> 'real time' <and> network	12/16/2004	MCH
EAST:character projection,circuit pattern,specification,parameter,cost,ti me,network,charged particle beam,mask,aperture,order	12/16/2004	MCH